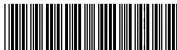


Search Notes**Application/Control No.**

10/537,329

Examiner

LOIS ZHENG

**Applicant(s)/Patent under
Reexamination**

NAKAYAMA ET AL.

Art Unit

1793

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---------------------|-----------|------|
| Inventorship search | 5/14/2009 | LLZ |
| Updated EAST Search | 5/26/2009 | LLZ |
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